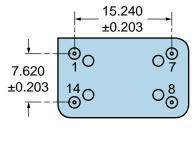


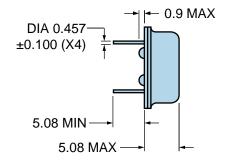
| ELECTRICAL SPECIFICATIONS | | |
|-----------------------------------|---|--|
| Nominal Frequency | 3.088MHz | |
| Frequency Tolerance/Stability | ±50ppm Maximum (Inclusive of all conditions: Calibration Tolerance at 25°C, Frequency Stability over the Operating Temperature Range,Supply Voltage Change, Output Load Change, First Year Aging at 25°C, Shock, and Vibration) | |
| Aging at 25°C | ±5ppm/year Maximum | |
| Operating Temperature Range | -20°C to +70°C | |
| Supply Voltage | 5.0Vdc ±10% | |
| Input Current | 45mA Maximum (Unloaded) | |
| Output Voltage Logic High (Voh) | Vdd-0.4Vdc Minimum (IOH = -16mA) | |
| Output Voltage Logic Low (Vol) | 0.4Vdc Maximum (IOL = +16mA) | |
| Rise/Fall Time | 4nSec Maximum (Measured at 20% to 80% of waveform) | |
| Duty Cycle | 50 ±10(%) (Measured at 1.4Vdc with TTL Load; Measured at 50% of waveform with HCMOS Load) | |
| Load Drive Capability | 50pF HCMOS Load Maximum | |
| Output Logic Type | CMOS | |
| Pin 1 Connection | Tri-State (Disabled Output: High Impedance) | |
| Pin 1 Input Voltage (Vih and Vil) | +2.0Vdc Minimum to enable output, +0.8Vdc to disable output, No Connect to enable output. | |
| Standby Current | 50μA Maximum (Pin 1 = Ground) | |
| Disable Current | 30mA Maximum (Pin 1 = Ground) | |
| Peak to Peak Jitter (tPK) | 500pSec Maximum, 90pSec Typical | |
| RMS Period Jitter (tRMS) | 50pSec Maximum, 13pSec Typical | |
| Start Up Time | 10mSec Maximum | |
| Storage Temperature Range | -55°C to +125°C | |

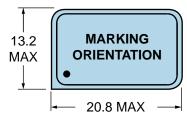
| ENVIRONMENTAL & MECHANICAL SPECIFICATIONS | | |
|---|---------------------------------------|--|
| Fine Leak Test | MIL-STD-883, Method 1014, Condition A | |
| Gross Leak Test | MIL-STD-883, Method 1014, Condition C | |
| Lead Integrity | MIL-STD-883, Method 2004 | |
| Mechanical Shock | MIL-STD-202, Method 213, Condition C | |
| Resistance to Soldering Heat | MIL-STD-202, Method 210 | |
| Resistance to Solvents | MIL-STD-202, Method 215 | |
| Solderability | MIL-STD-883, Method 2003 | |
| Temperature Cycling | MIL-STD-883, Method 1010 | |
| Vibration | MIL-STD-883, Method 2007, Condition A | |



MECHANICAL DIMENSIONS (all dimensions in millimeters)



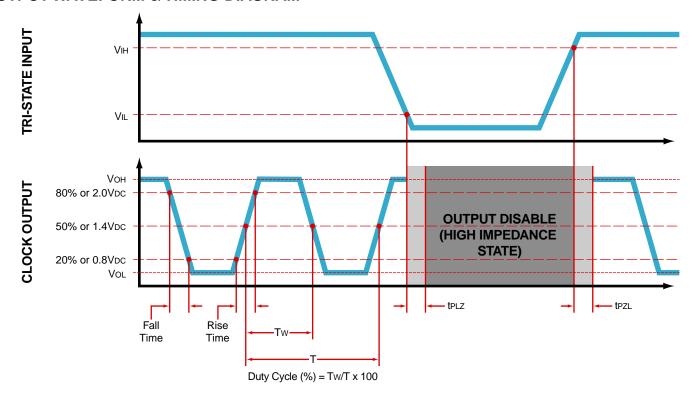




| PIN | CONNECTION |
|-----|----------------------------|
| 1 | Tri-State (High Impedance) |
| 7 | Ground/Case Ground |
| 8 | Output |
| 14 | Supply Voltage |

| LINE | MARKING |
|------|---|
| 1 | ECLIPTEK |
| 2 | EP11TS EP11=Product Series |
| 3 | 3.088M |
| 4 | XXYZZ XX=Ecliptek Manufacturing Code Y=Last Digit of the Year ZZ=Week of the Year |

OUTPUT WAVEFORM & TIMING DIAGRAM





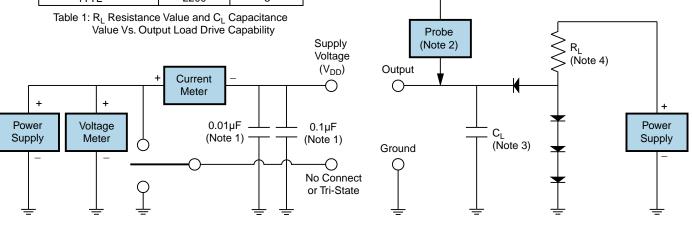
Frequency

Counter

Oscilloscope

Test Circuit for TTL Output

| Output Load Drive Capability | R _L Value (Ohms) | C _L Value (pF) |
|---------------------------------|--------------------------------|------------------------------|
| 10TTL | 390 | 15 |
| 5TTL | 780 | 15 |
| 2TTL | 1100 | 6 |
| 10LSTTL | 2000 | 15 |
| 1TTL | 2200 | 3 |



- Note 1: An external $0.1\mu F$ low frequency tantalum bypass capacitor in parallel with a $0.01\mu F$ high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.
- Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.
- Note 3: Capacitance value C_L includes sum of all probe and fixture capacitance.
- Note 4: Resistance value R_L is shown in Table 1. See applicable specification sheet for 'Load Drive Capability'.
- Note 5: All diodes are MMBD7000, MMBD914, or equivalent.



Test Circuit for CMOS Output



Note 1: An external $0.1\mu F$ low frequency tantalum bypass capacitor in parallel with a $0.01\mu F$ high frequency ceramic bypass capacitor close to the package ground and V_{DD} pin is required.

Note 2: A low capacitance (<12pF), 10X attenuation factor, high impedance (>10Mohms), and high bandwidth (>300MHz) passive probe is recommended.

Note 3: Capacitance value \dot{C}_L includes sum of all probe and fixture capacitance.



Recommended Solder Reflow Methods

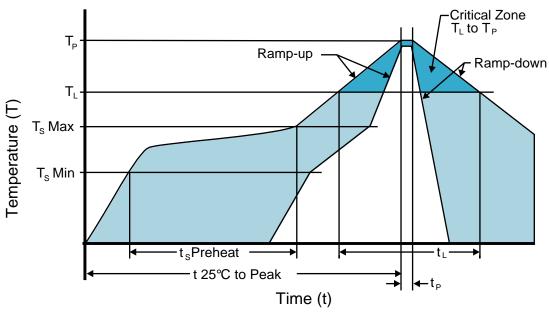


High Temperature Solder Bath (Wave Solder)

| | , | |
|---|--|--|
| T _s MAX to T _L (Ramp-up Rate) | 3°C/second Maximum | |
| Preheat | | |
| - Temperature Minimum (T _s MIN) | 150°C | |
| - Temperature Typical (T _s TYP) | 175°C | |
| - Temperature Maximum (T _s MAX) | 200°C | |
| - Time (t _s MIN) | 60 - 180 Seconds | |
| Ramp-up Rate (T _L to T _P) | 3°C/second Maximum | |
| Time Maintained Above: | | |
| - Temperature (T _L) | 217°C | |
| - Time (t _L) | 60 - 150 Seconds | |
| Peak Temperature (T _P) | 260°C Maximum for 10 Seconds Maximum | |
| Target Peak Temperature (T _P Target) | 250°C +0/-5°C | |
| Time within 5°C of actual peak (tp) | 20 - 40 seconds | |
| Ramp-down Rate | 6°C/second Maximum | |
| Time 25°C to Peak Temperature (t) | 8 minutes Maximum | |
| Moisture Sensitivity Level | Level 1 | |
| Additional Notes | Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option. | |
| | | |



Recommended Solder Reflow Methods



Low Temperature Infrared/Convection 185°C

| • | | |
|---|---|--|
| T _s MAX to T _L (Ramp-up Rate) | 5°C/second Maximum | |
| Preheat | | |
| - Temperature Minimum (T _s MIN) | N/A | |
| - Temperature Typical (T _s TYP) | 150°C | |
| - Temperature Maximum (T _s MAX) | N/A | |
| - Time (t _s MIN) | 60 - 120 Seconds | |
| Ramp-up Rate (T _L to T _P) | 5°C/second Maximum | |
| Time Maintained Above: | | |
| - Temperature (T _L) | 150°C | |
| - Time (t∟) | 200 Seconds Maximum | |
| Peak Temperature (T _P) | 185°C Maximum | |
| Target Peak Temperature (T _P Target) | 185°C Maximum 2 Times | |
| Time within 5°C of actual peak (tp) | 10 seconds Maximum 2 Times | |
| Ramp-down Rate | 5°C/second Maximum | |
| Time 25°C to Peak Temperature (t) | N/A | |
| Moisture Sensitivity Level | Level 1 | |
| Additional Notes | Temperatures shown are applied to body of device. Use this method only for product with the Gull Wing option. | |
| | | |



Recommended Solder Reflow Methods



Low Temperature Solder Bath (Wave Solder)

| | , | |
|---|--|--|
| T _s MAX to T _∟ (Ramp-up Rate) | 5°C/second Maximum | |
| Preheat | | |
| - Temperature Minimum (T _S MIN) | N/A | |
| - Temperature Typical (T _s TYP) | 150°C | |
| - Temperature Maximum (T _s MAX) | N/A | |
| - Time (t _s MIN) | 30 - 60 Seconds | |
| Ramp-up Rate (T _L to T _P) | 5°C/second Maximum | |
| Time Maintained Above: | | |
| - Temperature (T _L) | 150°C | |
| - Time (t∟) | 200 Seconds Maximum | |
| Peak Temperature (T _P) | 245°C Maximum | |
| Target Peak Temperature (T _P Target) | 245°C Maximum 1 Time / 235°C Maximum 2 Times | |
| Time within 5°C of actual peak (t _p) | 5 seconds Maximum 1 Time / 15 seconds Maximum 2 Times | |
| Ramp-down Rate | 5°C/second Maximum | |
| Time 25°C to Peak Temperature (t) | N/A | |
| Moisture Sensitivity Level | Level 1 | |
| Additional Notes | Temperatures shown are applied to back of PCB board and device leads only. Do not use this method for product with the Gull Wing option. | |
| | | |

Low Temperature Manual Soldering

185°C Maximum for 10 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)

High Temperature Manual Soldering

260°C Maximum for 5 seconds Maximum, 2 times Maximum. (Temperatures listed are applied to device leads only. This method can be utilized with both Gull Wing and Non-Gull Wing devices.)